

Electrical Contact Performance of Gold-Plated Pins

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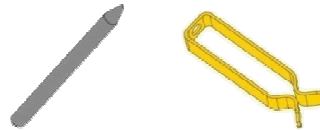
3 November 2010

Overview

- **Background**
- **Problem**
- **Statement of work**
- **Test setup**
- **Test plan**
- **Analytical model**
- **Results & Analysis**
 - **Contact resistance calculations**
- **Conclusions**
- **Additional outcomes**
- **Lessons learned**

Background

- **Precision electro-mechanical switch**
- **Several electrical contact pairs, consisting of**
 - Pin
 - **Receptacle**
- **Current materials: alloys with high gold content**
- **Similar, older devices used gold-plated pins**

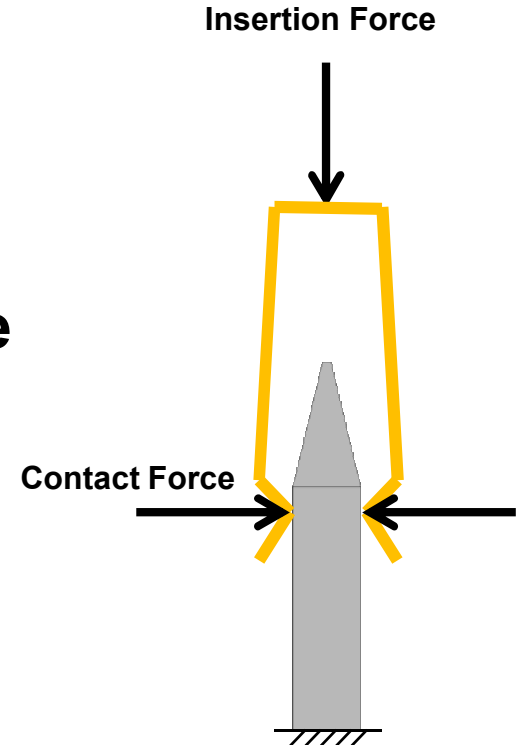


Problem

- **PROBLEM:** Need to find a way to reduce CR without raising insertion force
- **HYPOTHESIS:** Gold-plating the pin contacts will solve this problem

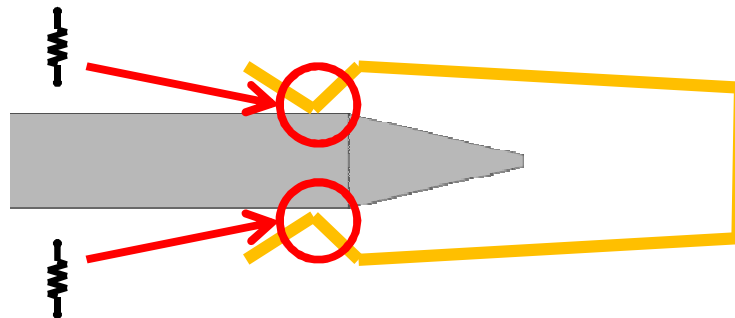
Definitions

- **Contact force:** force due to the spring-like nature of the receptacle, normal to the contact surfaces (usually when fully displaced, i.e. on cylinder)
- **Insertion (or friction) force:** force due to friction between the (pin and receptacle) surfaces, required to insert the pin into the receptacle; function of contact force and friction coefficient



Definitions

- **Contact resistance:** the resistance at the interface between the contact surface(s) of the pin and the receptacle



Statement of Work

- **Determine how gold-plating the pin contacts will affect their performance**
- **Evaluate contact performance according to two (2) criteria:**
 - The **electrical contact resistance** at the pin-receptacle interface
 - The **insertion force** resulting from pin-receptacle interaction

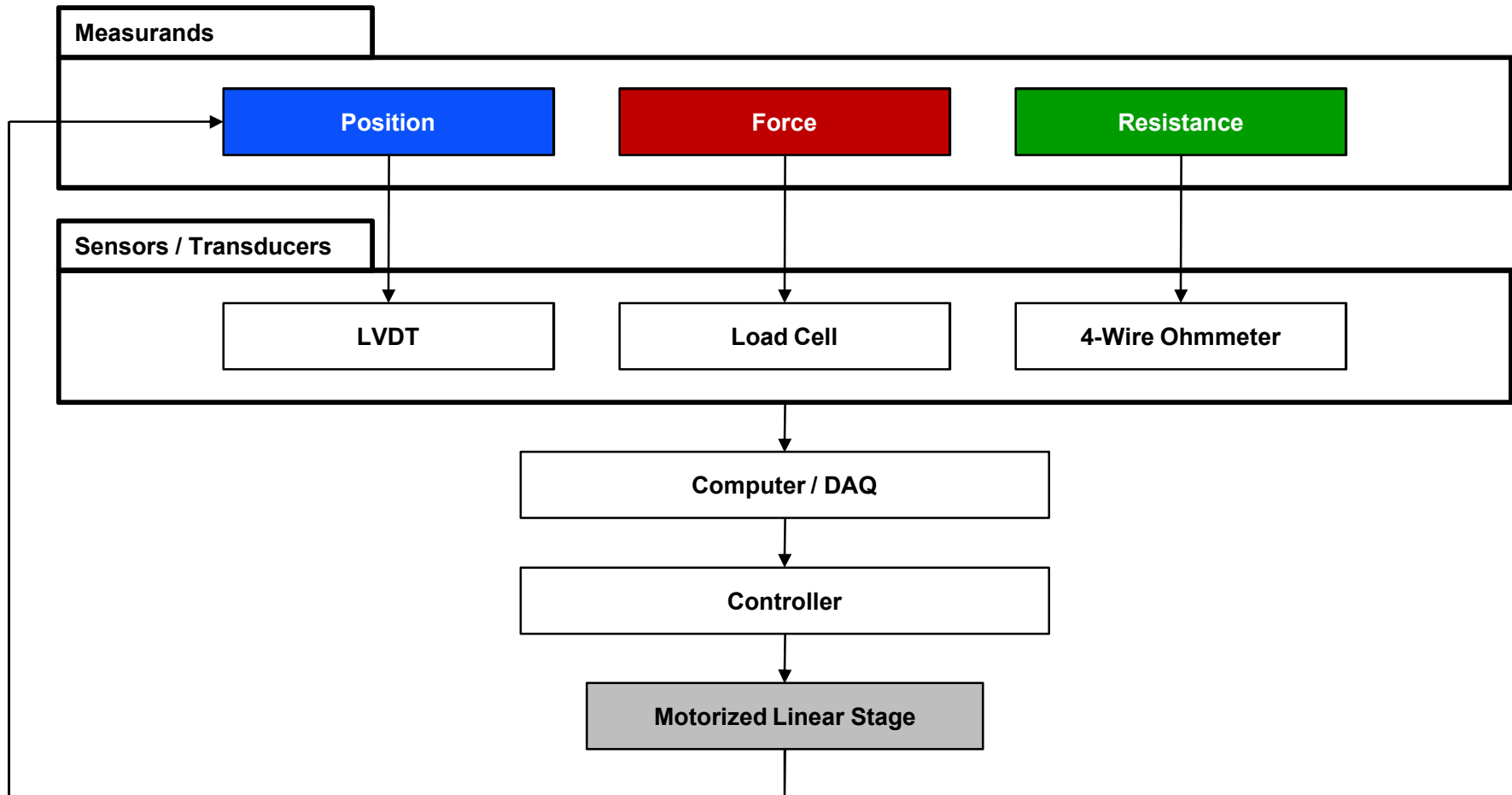
Test Setup – Requirements

- **Perform tests using realistic design configuration**
- **Use existing, available hardware**
- **Parts must be submersed in silicone oil during test**
- **3 measurands**
 - **Position (travel/stroke): < 0.400”**
 - **Force (insertion & removal forces): < 20 grams-force**
 - **Electrical resistance (contact resistance): < 40 mΩ**

Test Setup – Challenges

- **Examine a single pin-receptacle contact pair**
- **Ensure proper alignment of parts**
- **Submerge parts in silicone oil during test**
- **Minimize measurement intrusiveness**
- **Resistance measurements**
 - **Reliable, consistent electrical connection points**
 - **Eliminate lead resistance**
- **Force measurements**
 - **Minimize additional weight due to electrical connections, fixtures**

Test Setup – Block Diagram

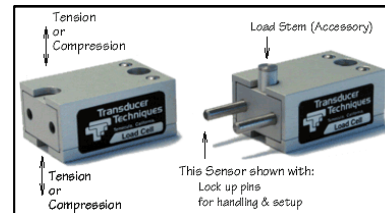


Test Setup – Instruments & Transducers

- **Electrical resistance**
 - 4-wire milliohmmeter,
100 mΩ
- **Force**
 - Precision load cell,
25 g
- **Position**
 - Linear variable differential transformer (LVDT),
0.3938” stroke
- **Data acquisition (DAQ) unit**
 - Digital oscilloscope,
20 S/s (up to 2 GS/s)



HP 4328 milliohmmeter
 Range: 1 mΩ – 100 Ω
 Accuracy: ± 2% of full scale
 Measuring frequency:
 1000 Hz ± 100 Hz



Transducer Techniques, GSO Series
 Tension or compression
 Linearity: 0.05% of read out (R.O.)
 Hysteresis: 0.05% of R.O.
 Repeatability: 0.05% of R.O.
 Zero balance: 1.0% of R.O.
 Temp. effect on output: 0.005% of load/°F
 Temp. effect on zero: 0.005% of R.O./°F



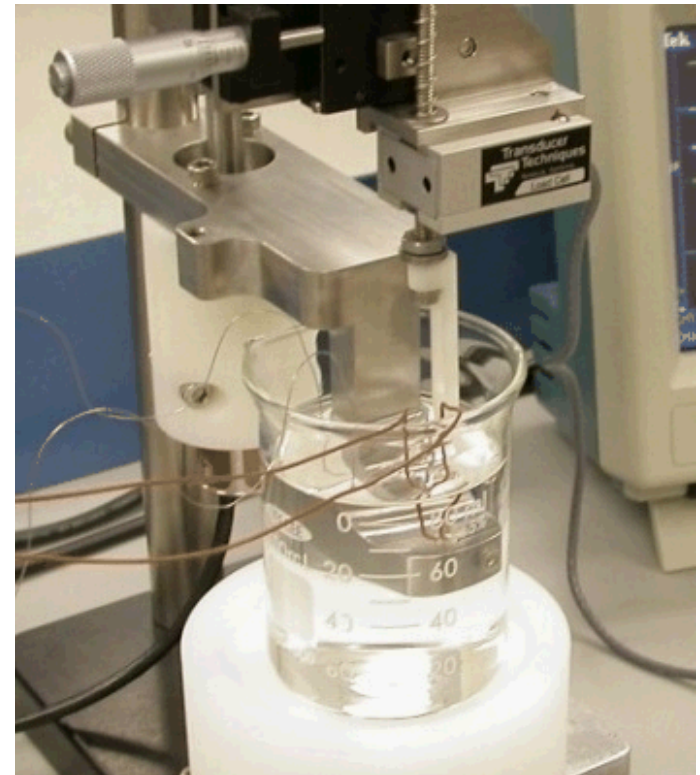
RDP Electrosense, DCTH200AG
 Travel range: ± 5 mm (± 0.1969 in)
 Linearity: 0.24% (% F.S.)



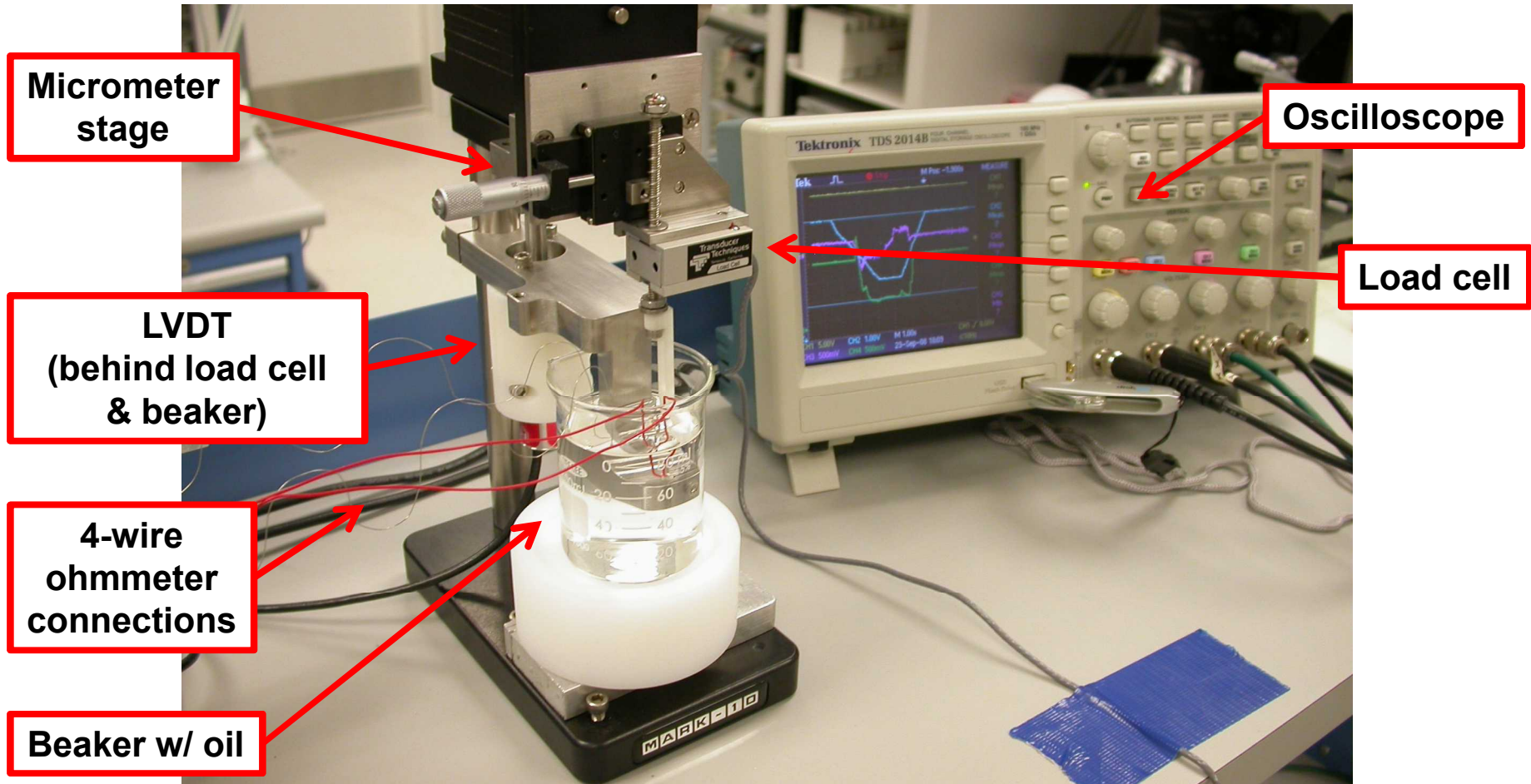
Tektronix TDS644A
 500 MHz max analog bandwidth
 Up to 2 Gs/s
 4 channels
 Up to 2000-sample record length per channel
 8-bit digitizer

Test Setup – Sample Environment

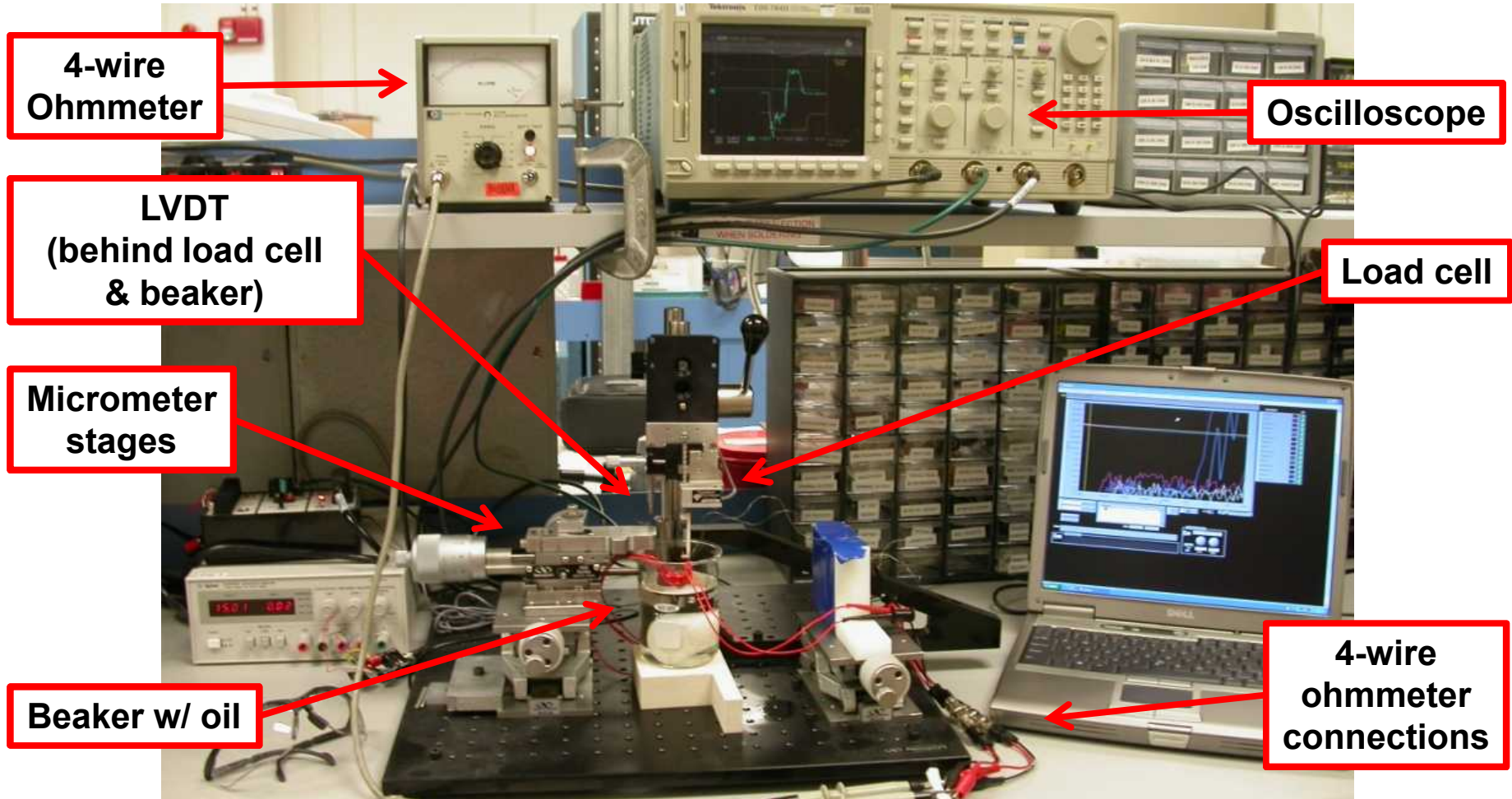
- **Controlled environment**
 - Test samples were submerged in an oil bath
 - **Silicone oil, low viscosity**
 - Beaker, 250 mL
- **Ambient conditions**
 - Temperature
 - Pressure



Test Setup – Actual Setup (OLD)



Test Setup – Actual Setup (Modified)



Test Setup – Summary of Capabilities

Measurand	Unit	Span	Accuracy	Resolution *
Position	inches	0.3938	< 0.0010	± 0.0016
Force	grams (force)	25	0.1	± 0.05
Resistance	milliOhms	100	.020	± 0.4

* Resolution depended on A-to-D (i.e., specs & settings)

Test Plan – Samples

**PIN TYPE
(3 levels)**



Type A

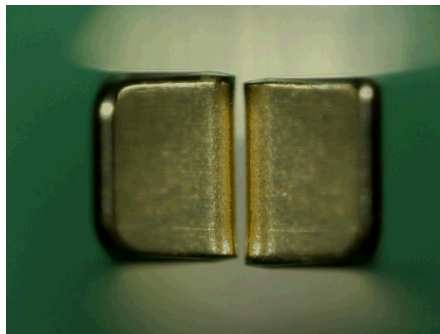


Type B



**Type C
(gold-plated)**

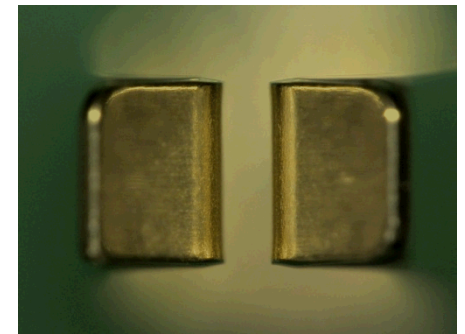
**RECEPTACLE
GAP SIZE
(3 levels)**



0.004" gap



0.010" gap



0.016" gap

Test Plan – Samples

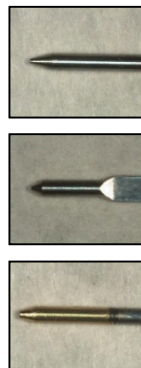
- **2 factors**
 - Pin type (3 levels)
 - Gap size (3 levels)
- **1 replicate of each combination**
- **Full factorial**

Std Order	Run Order	Pin ID	Recep ID	Gap
1	3	PA-1	R04-1	0.004
2	6	PA-2	R10-1	0.010
3	8	PA-3	R16-1	0.016
4	9	PB-1	R04-2	0.004
5	4	PB-2	R10-2	0.010
6	7	PB-3	R16-2	0.016
7	2	PC-1	R04-3	0.004
8	5	PC-2	R10-3	0.010
9	1	PC-3	R16-3	0.016

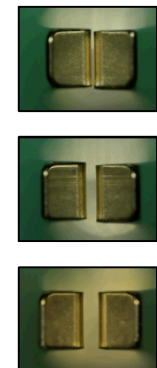
x 2

3 x 3 x 2 = 18 pairs/combinations

Pin Type
PA = Type A
PB = Type B
PC = Type C

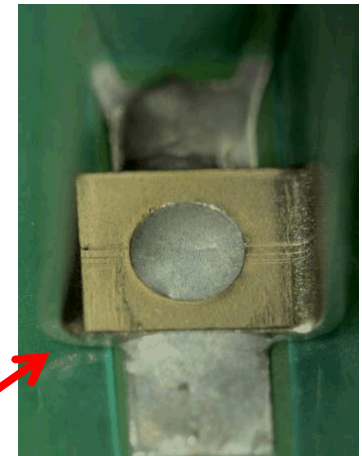
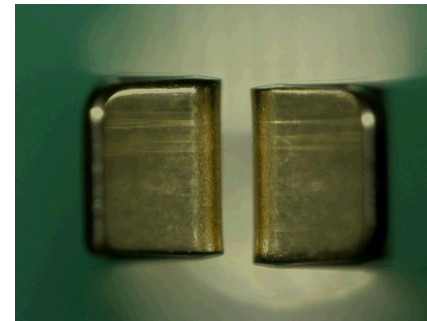
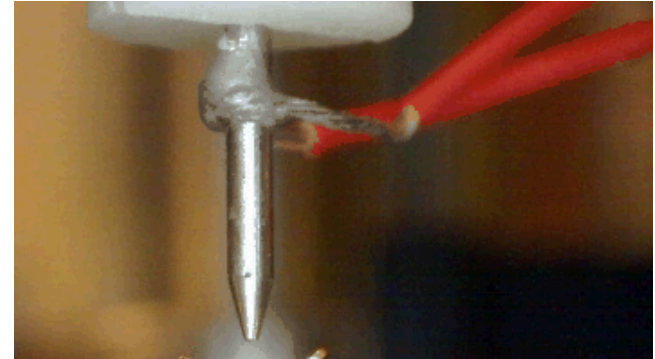


Receptacle Gap
0.004"
0.010"
0.016"



Test Plan – Sample Preparation

- **All samples**
 - Performed visual inspection
 - Cleaned samples with detergent in ultrasonic cleaner
- **18 Pins**
 - Soldered wires to pins
- **18 Receptacles**
 - Adjusted & measured receptacle gap sizes w/ optical comparator
 - Heat-treated receptacles
 - Mounted/soldered receptacles to printed circuit board (PCB) fixtures
 - Checked receptacle gap size using digital microscope; re-adjusted, if needed
 - Soldered wires to PCB

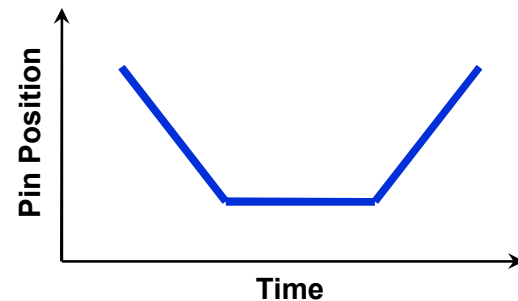
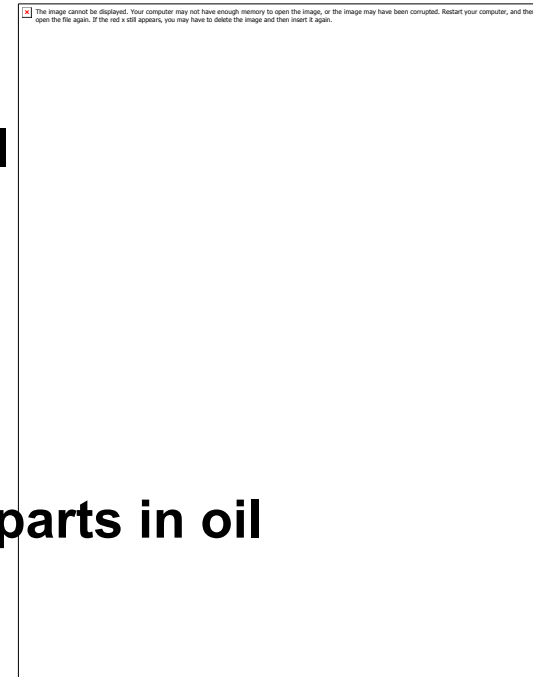
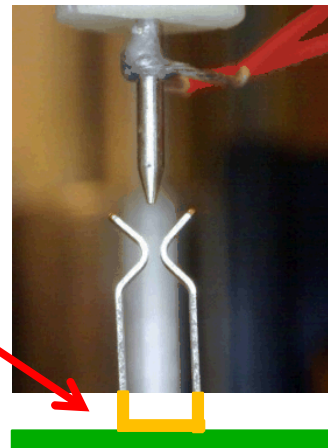


**Base of
receptacle &
solder joint**

Test Plan – Procedure

- Insert pin into collet, attach collet to load cell
- Attach PCB w/ receptacle to tester
- Visually align pin and receptacle
- Connect wires from pin and receptacle to 4-wire ohmmeter
- Pour silicone oil into breaker and submerge parts in oil
- Run test: **down-dwell-up**
 - NOTE: During test receptacle remains fixed, pin is inserted downward into receptacle
- Record data

Base of receptacle soldered to PCB



Test Plan – Procedure

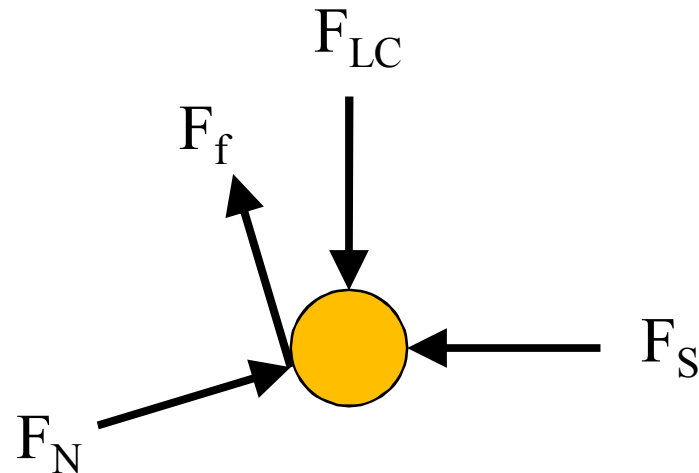
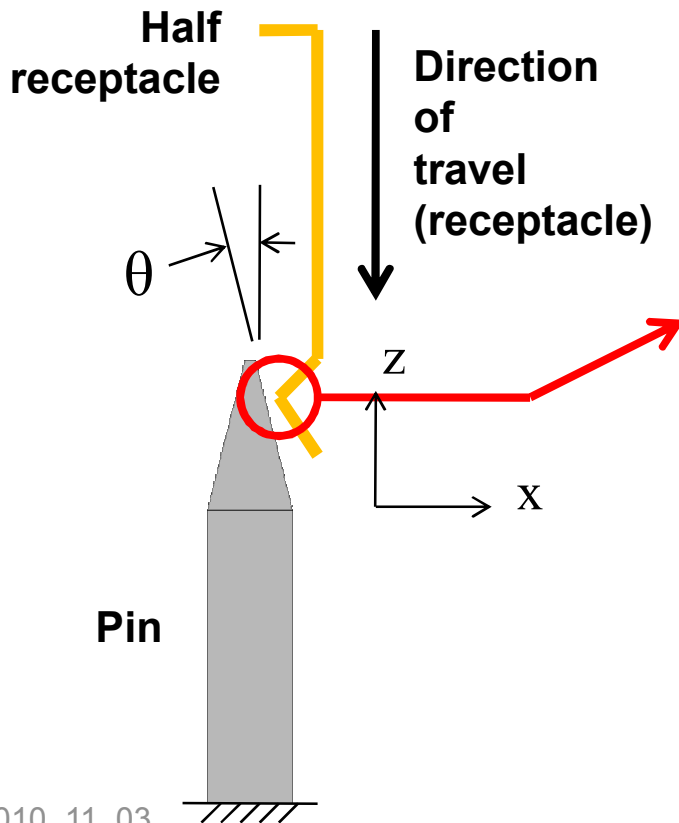
- **Certain data were selected for storage & analysis**
- **Each pair tested multiple times**
 - **5 repetitions in order to observe possible variation between runs**
 - **Repetitions 1, 3, and 5 were recorded**
- **Total: $18 \times 3 = 54$ data sets**
 - **Each set has 25 seconds of data @ 20 samples/sec**
 - **Each set includes position, force, resistance vs. time**

Analytical Model – Expected Force

- **A simple analytical model was created for comparison with test data, to predict expected curve**
 - **Assumptions:**
 - **Half receptacle modeled as cantilever with end being displaced by pin**
 - **Receptacle traveling downward at constant velocity along the pin**
 - **Contact point on receptacle modeled as particle**
 - **Weight of receptacle neglected**
 - **Acceleration = 0 since velocity assumed to be constant (approx. constant during test)**

Analytical Model – Expected Force

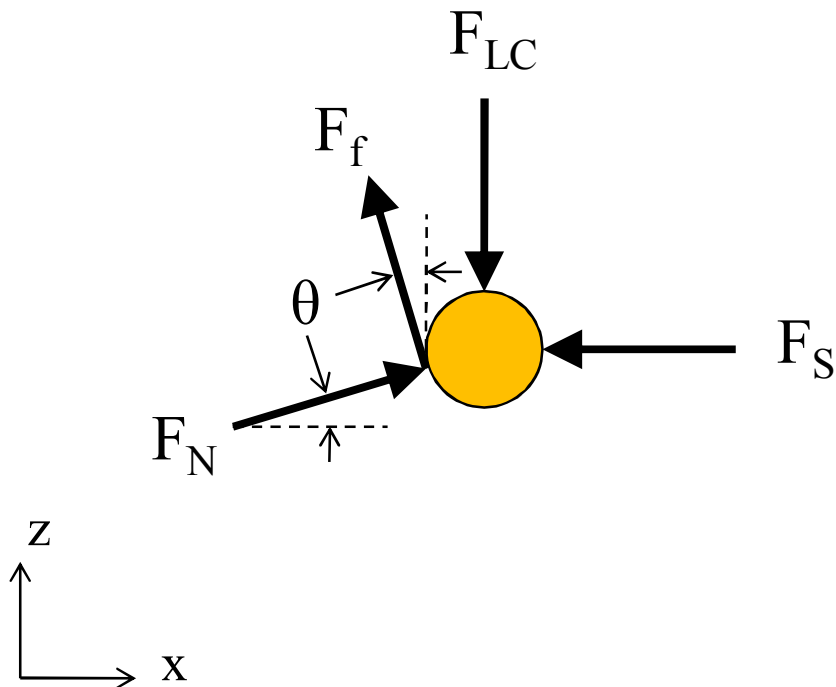
• **FDB:**



F_{LC}	= force, downward (seen by load cell)
F_S	= force, spring (receptacle)
F_f	= force, friction
F_N	= force, normal
θ	= cone angle = 15 deg (from vertical)

Analytical Model – Expected Force

- Model equations:



$$\Sigma F_x = m a_x = 0:$$

$$-F_s + F_n \cos \theta - F_f \sin \theta = 0$$

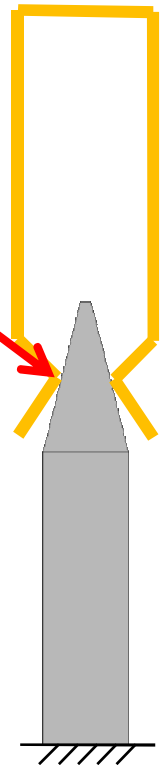
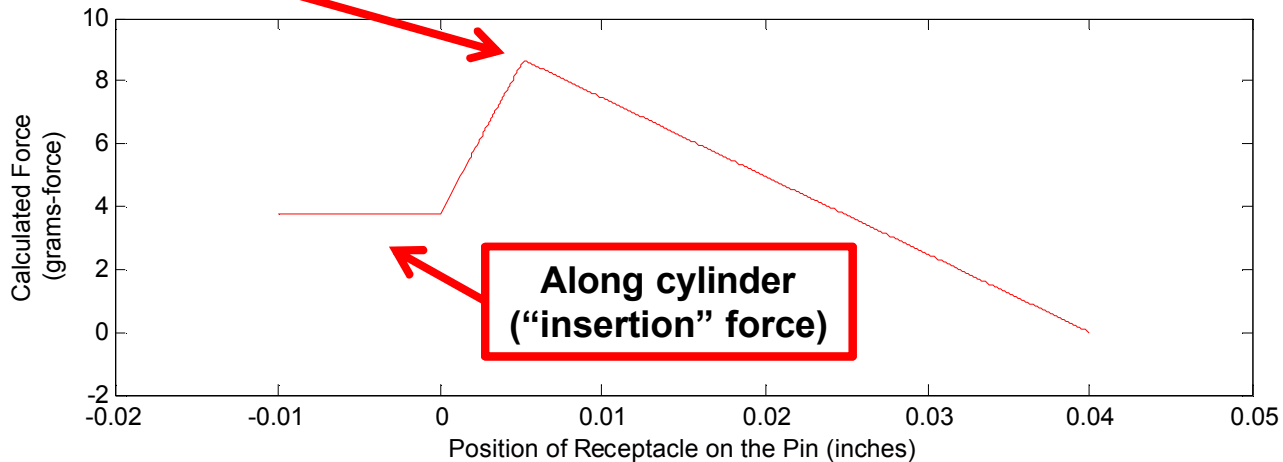
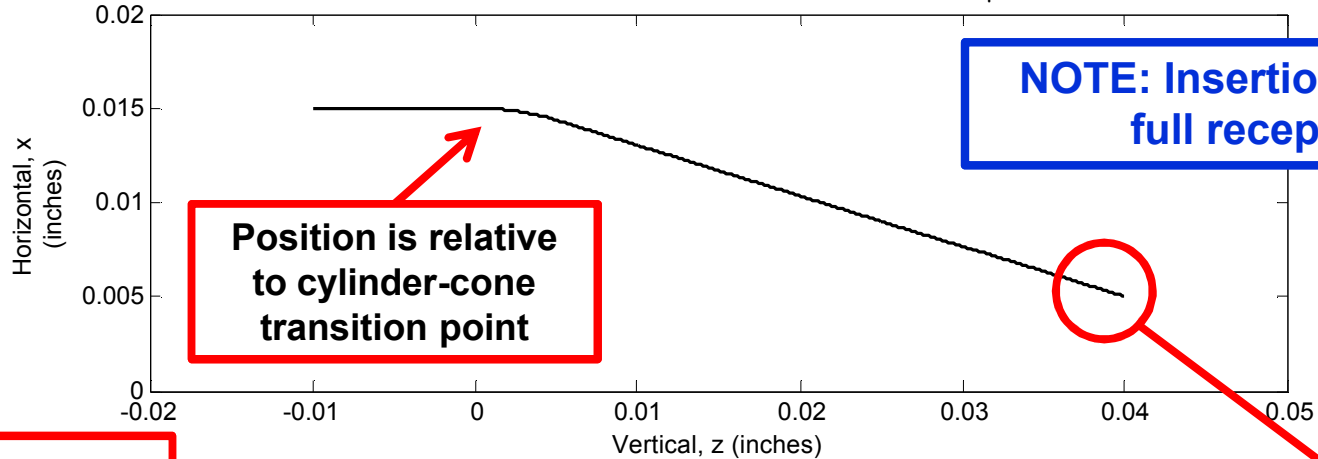
$$\Sigma F_z = m a_z = 0:$$

$$-F_{LC} + F_f \cos \theta + F_n \sin \theta = 0$$

$$\begin{aligned} F_s &= (k) (\text{interference}) \\ F_n &= (F_s) / (\cos \theta - \mu \sin \theta) \\ F_f &= (\mu) (F_n) \\ \mathbf{F}_{LC} &= \mathbf{F}_f \cos \theta + \mathbf{F}_n \sin \theta \\ &= \frac{1}{2} \text{ INSERTION FORCE} \end{aligned}$$

Analytical Model – Force vs. Position

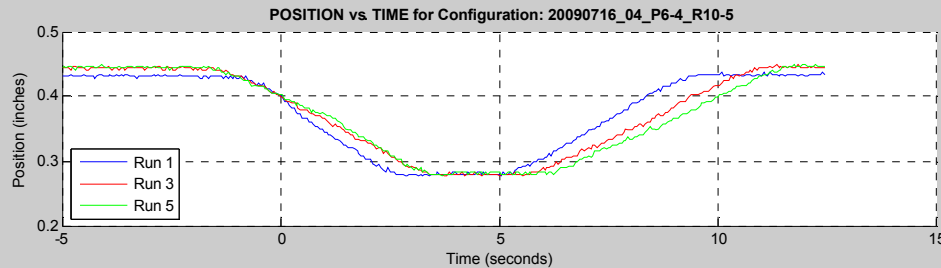
Pin-Receptacle Interaction: Expected Force Profile for Full Receptacle
 Gap: 0.010" | Max interference: 0.010" | $k = 938.90$ | $\mu = 0.20$



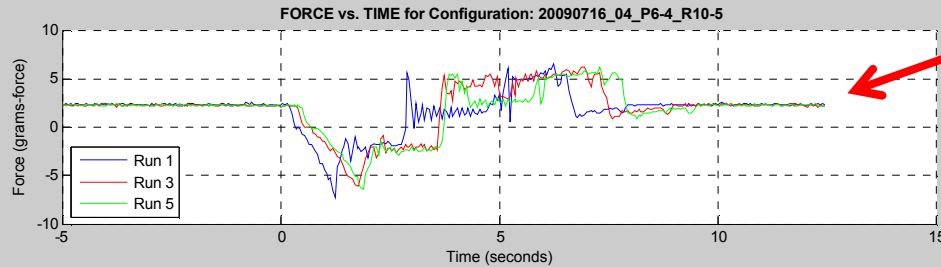
Results – Representative Data

Type A pin with 0.010" receptacle gap

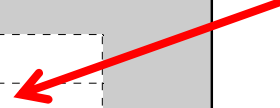
Position



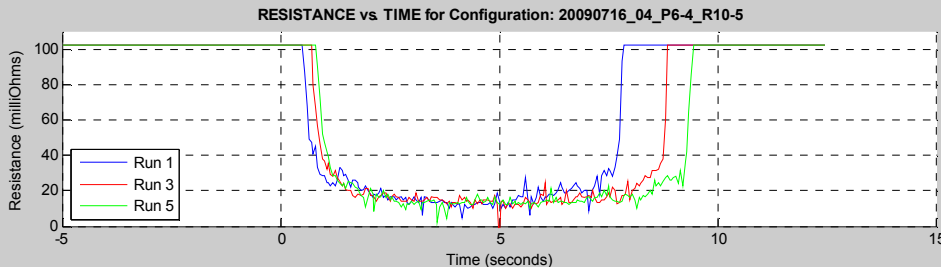
Force



NOTE:
Zero offset
(force only)



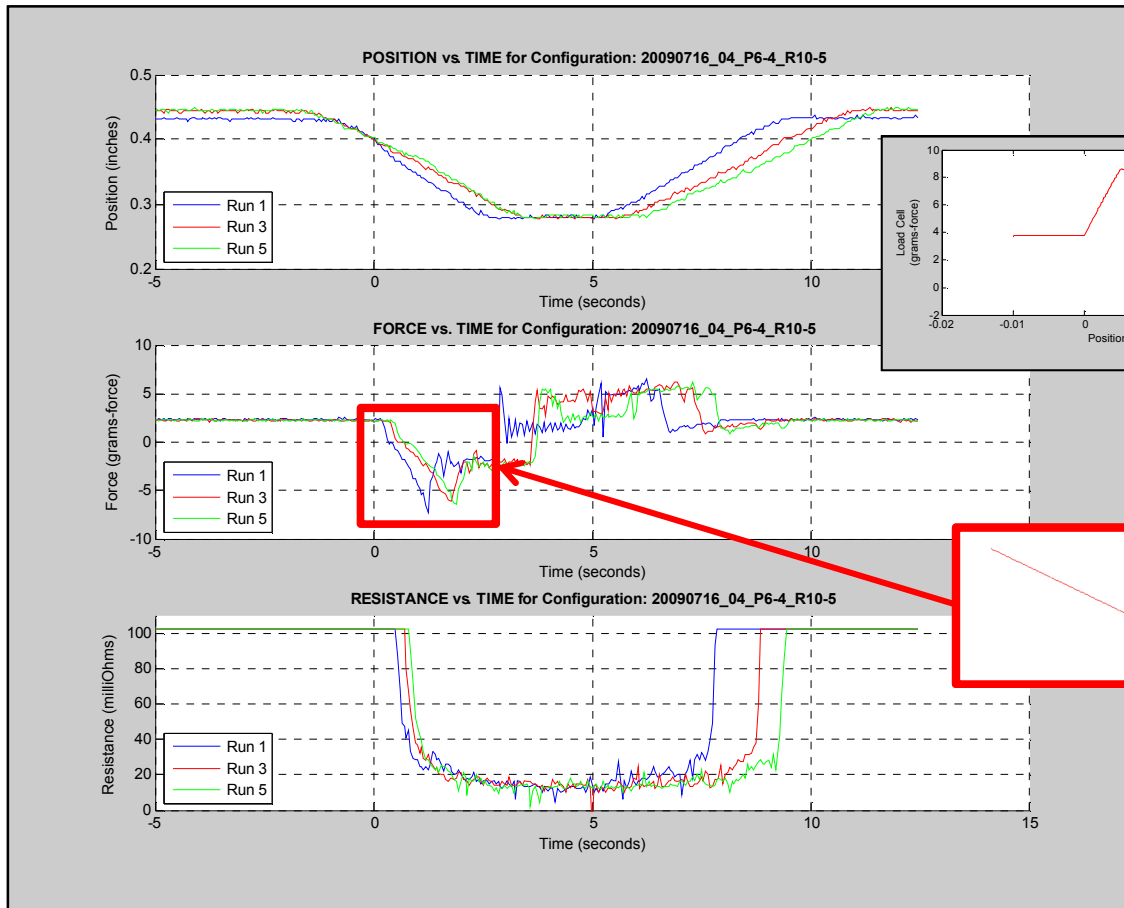
Resistance



Results – Representative Data

Type A pin with 0.010" receptacle gap

Position



Force



Resistance

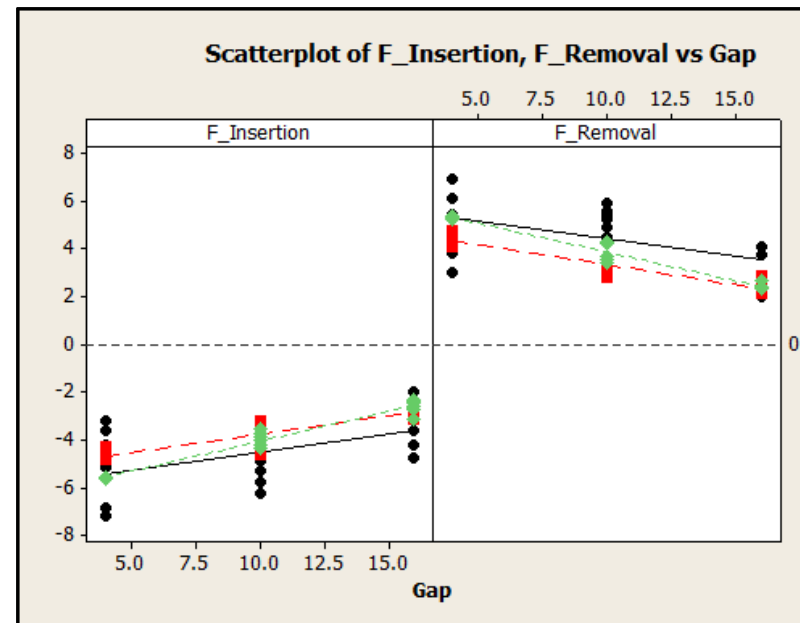


Results – Force

- Linear relationship between force and gap size
- Gold-plated pins have highest peak, insertion, and removal forces

$N_i = 6$

Material	Gap (mil)	Statistical Measure	Peak Force (g)	Cylinder Insertion Force (g)	Cylinder Removal Force (g)
PA	10	MEAN	-9.4	-3.9	3.1
		STDEV	2.0	0.6	0.2
PB	10	MEAN	-10.1	-4.0	3.9
		STDEV	0.7	0.3	0.4
PC	10	MEAN	-11.5	-5.2	5.2
		STDEV	2.3	0.7	0.5



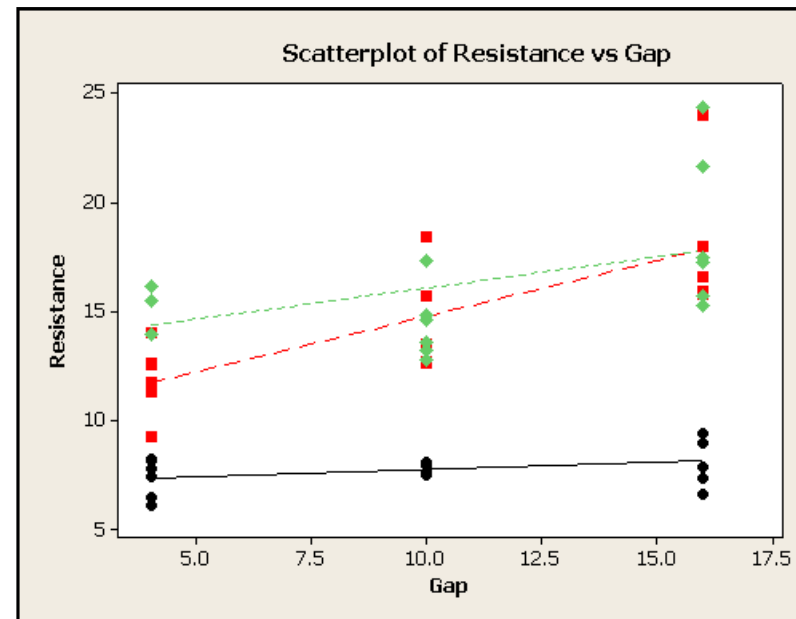
Results – Total Resistance

- Resistance increases slightly as gap increases
- Gold-plated pins exhibit a nearly constant resistance regardless of gap size

 $N_i = 6$

– At nominal gap width, this value is half that of PA & PB

Material	Gap (mil)	Statistical Measure	Total Resistance (mΩ)
PA	10	MEAN	14.41
		STDEV	2.27
PB	10	MEAN	14.40
		STDEV	1.63
PC	10	MEAN	7.71
		STDEV	0.22



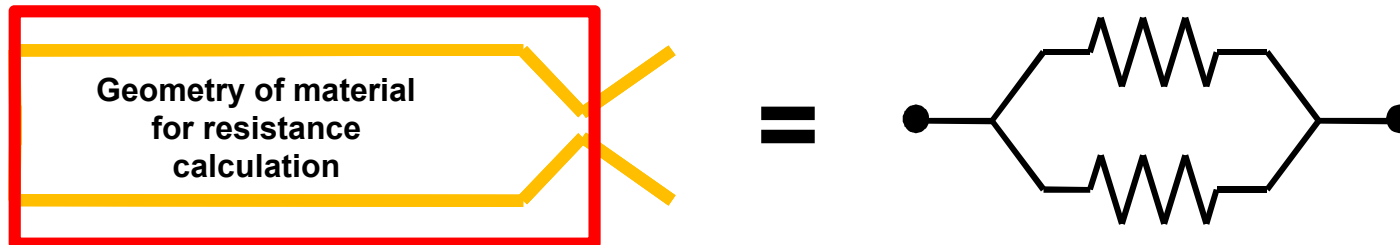
Calculating Contact Resistance

- **Circuit resistance (R_{circuit}):** combined resistance due to multiple contact pairs (i.e., one circuit) in the switch
- **Total resistance (R_{total}):** electrical resistance measured
- **Bulk resistance (R_{bulk}):** resistance due to material & geometry
 - Receptacle as 2 resistors in parallel
 - Pin as cylinder
- **Contact resistance, (CR or R_{CR}):** resistance at interface between pin & receptacle contacts

$$R_{\text{CR}} = R_{\text{total}} - R_{\text{bulk}}$$

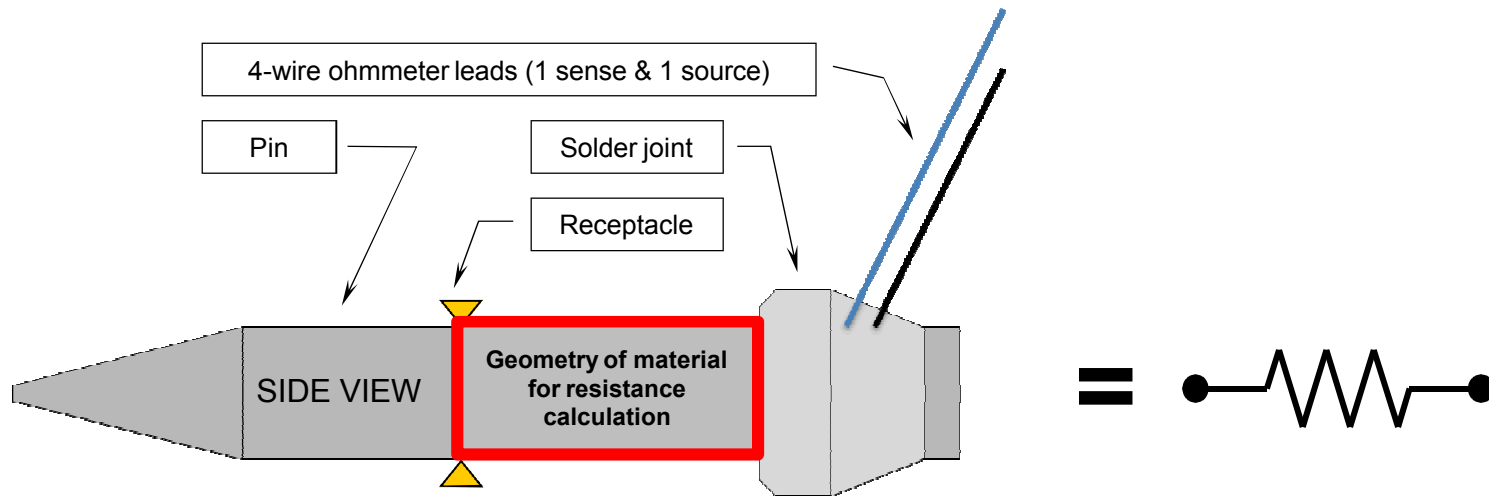
Calculating Contact Resistance

- Bulk resistance includes resistance from **receptacle**
- Calculated as 2 resistors in parallel
- Nominal geometry assumed



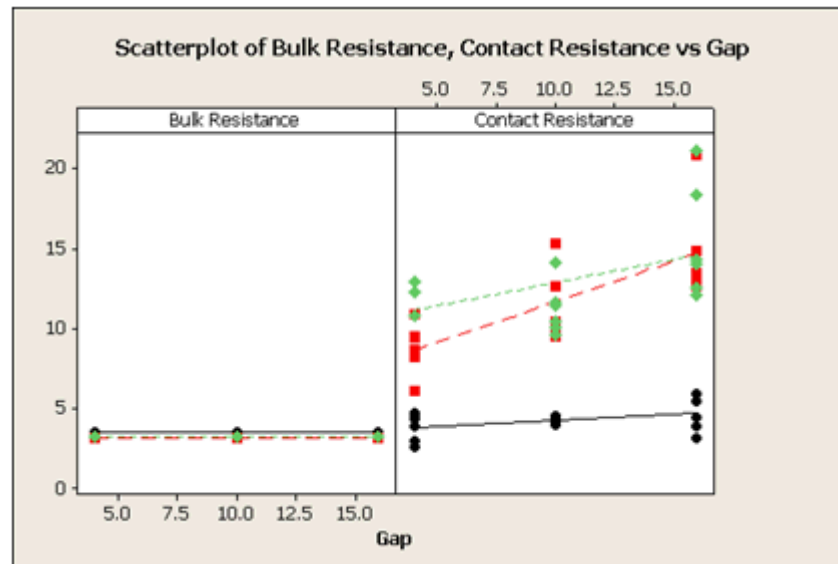
Calculating Contact Resistance

- Bulk resistance includes resistance from **pin**
- Calculated as a single resistor
- Nominal geometry assumed
- Gold-plating neglected for Type C pin



Results – Resistance (Bulk vs. CR)

- **Contact resistance is more significant than the bulk resistance (contributed by the material)**
- **The contact resistance of the gold-plated pin is nearly equal to the bulk resistance of the contacts**
 - Significantly lower than the Type A, Type B pins



Results – Gold-Plated Comparison (Nominal)

 $N_i = 6$

Material	Gap (mil)	Statistical Measure	FORCE			ELECTRICAL RESISTANCE				
			Peak Force (g)	Cylinder Insertion Force (g)	Cylinder Removal Force (g)	Total Resistance (mΩ)	Receptacle Resistance (mΩ)	Pin Resistance (mΩ)	Bulk Resistance (mΩ)	Contact Resistance (mΩ)
PA	10	MEAN	-9.4	-3.9	3.1	14.41	2.65	0.58	3.23	11.18
		STDEV	2.1	0.6	0.2	2.27	0.00	0.00	0.00	2.27
PB	10	MEAN	-10.1	-4.0	3.9	14.40	2.65	0.71	3.36	11.04
		STDEV	0.7	0.3	0.4	1.63	0.00	0.00	0.00	1.63
PC	10	MEAN	-11.5	-5.3	5.3	7.71	2.65	0.97	3.62	4.09
		STDEV	2.3	0.7	0.5	0.22	0.00	0.00	0.00	0.22

PC vs PA	10	MEAN	+23%	+35%	+72%	-46%	-	+67%	+12%	-63%
PC vs PB	10	MEAN	+14%	+32%	+35%	-46%	-	+37%	+8%	-63%

Conclusions

- **RE-STATEMENT OF PROBLEM:** Need to find a way to reduce CR without raising insertion force
- Comparatively, the Type C gold-plated pin produces **lower contact resistance**; however, it also exhibits higher insertion force
 - **Gold-plating therefore seems to introduce a trade-off between lower contact resistance and higher friction**
- Contact force (and thus insertion force) is a linear function of contact interference, as expected
- Type A and Type B pins are almost identical in performance



Additional Outcomes

- **Characterization of pins and receptacles**
- **Useful setup for testing future contacts**
- **Test setup for other types of switches**

Lessons Learned

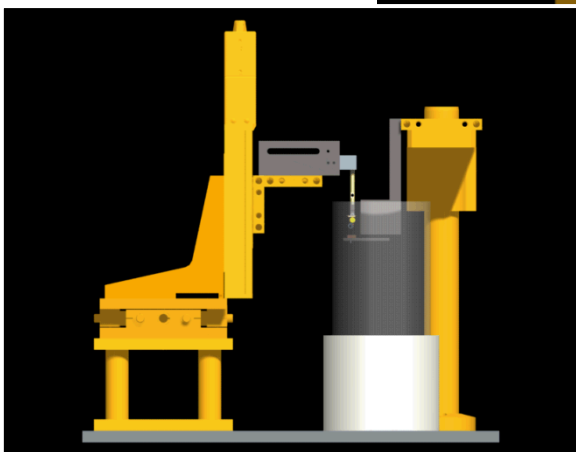
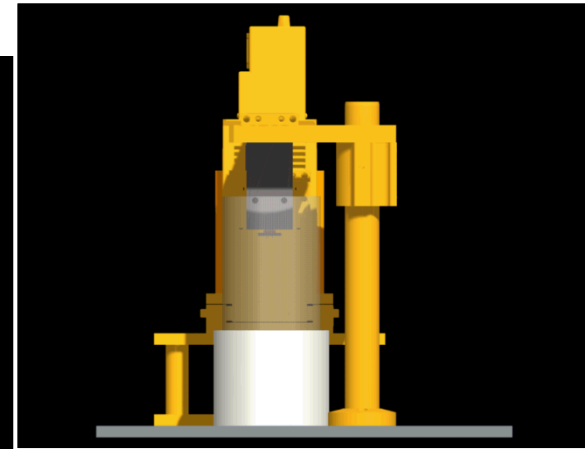
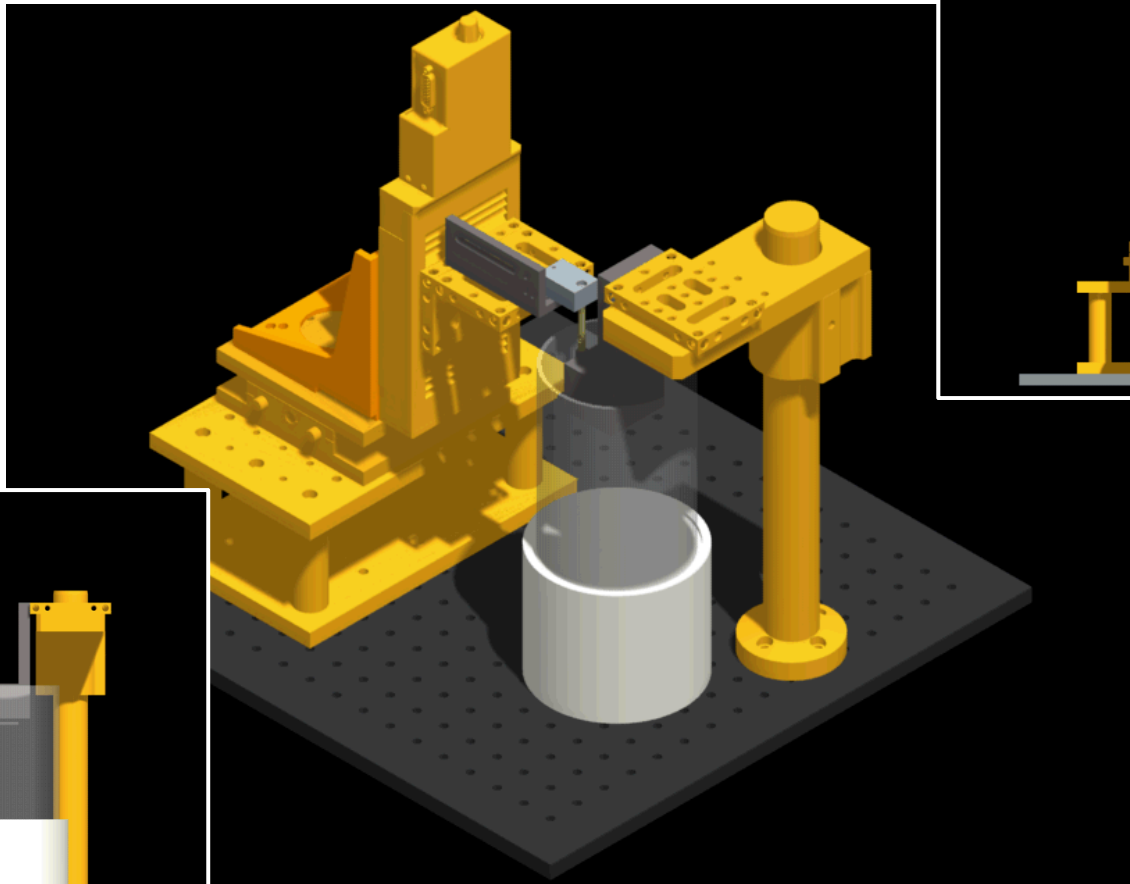
- **Due to size of samples (miniature scale), better environmental controls can and should be implemented in order to minimize variance in measurements caused by changes in temperature, pressure, humidity, etc.**
- **Ensure that pedigree of all parts/samples is known and traceable**
- **Find a better way to align parts**
 - **Image sensing control system?**
- **Use a motorized precision linear stage to achieve desired motion**
 - **NOTE: This has been implemented in the test setup**
- **Consistency!**

References

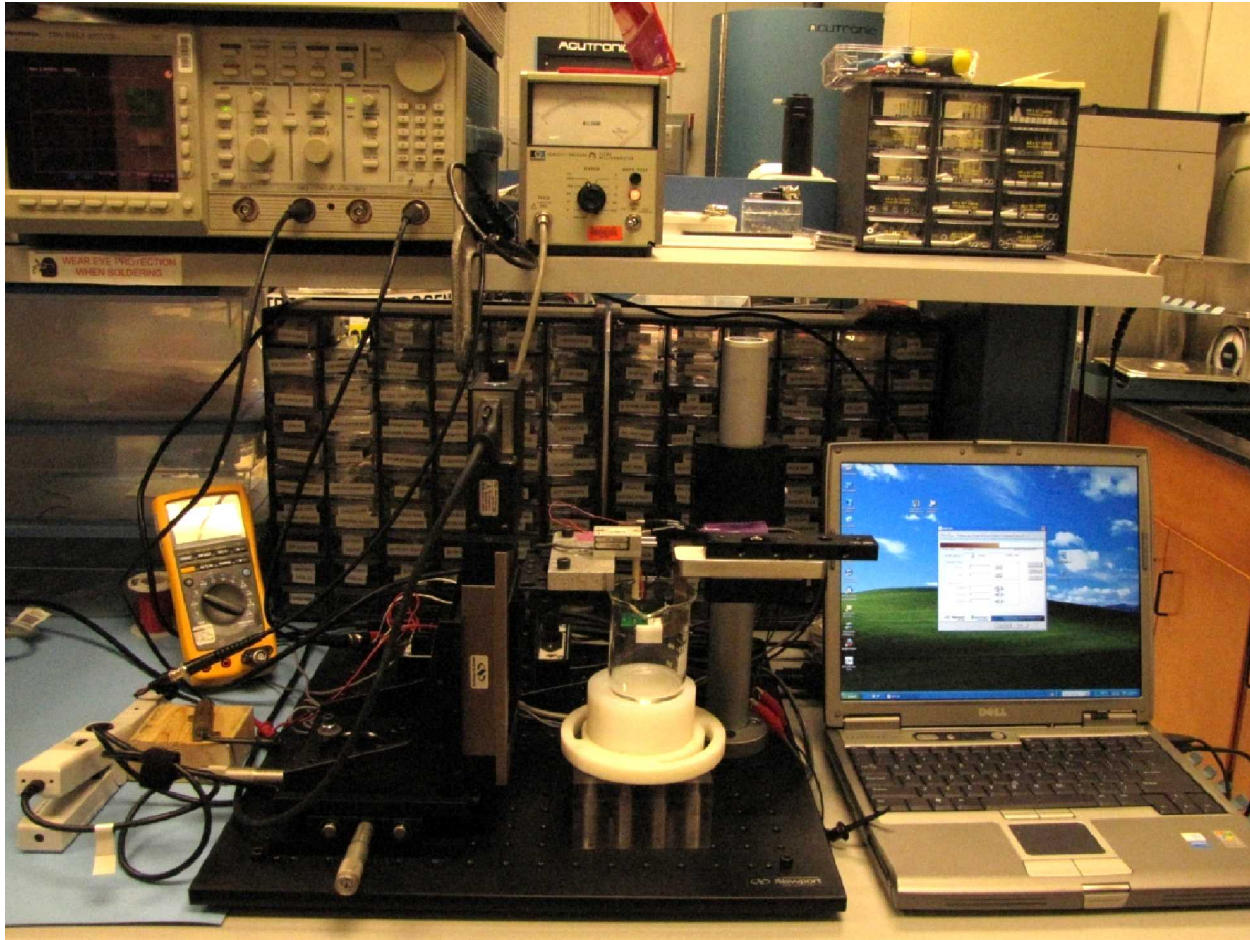
- **SNL presentation by G. Benavides**
- **Part drawings & documents**
- **K. Pitney, *Ney Contact Manual* (1973)**
- **Material properties from alloy manufacturer**

EXTRA SLIDES FOLLOW

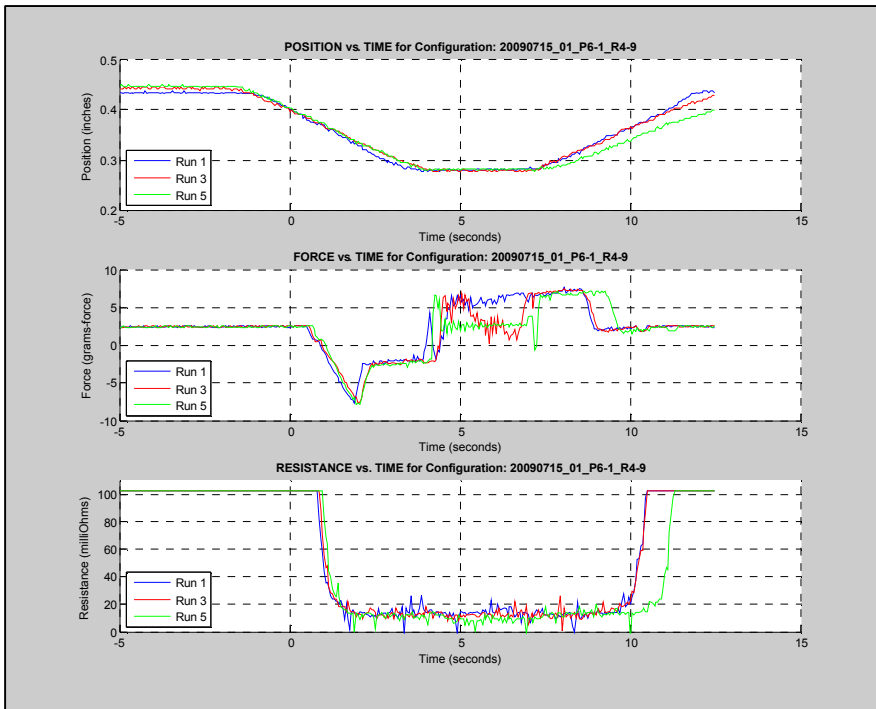
Test Setup – Planned Modification



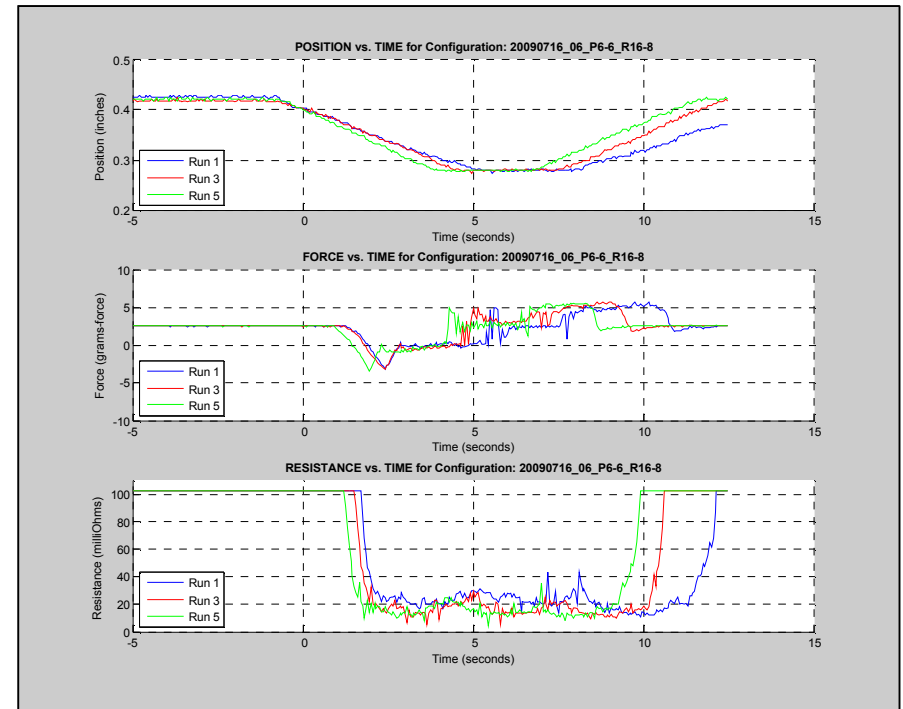
Test Setup – Current Configuration



Results – Representative Data



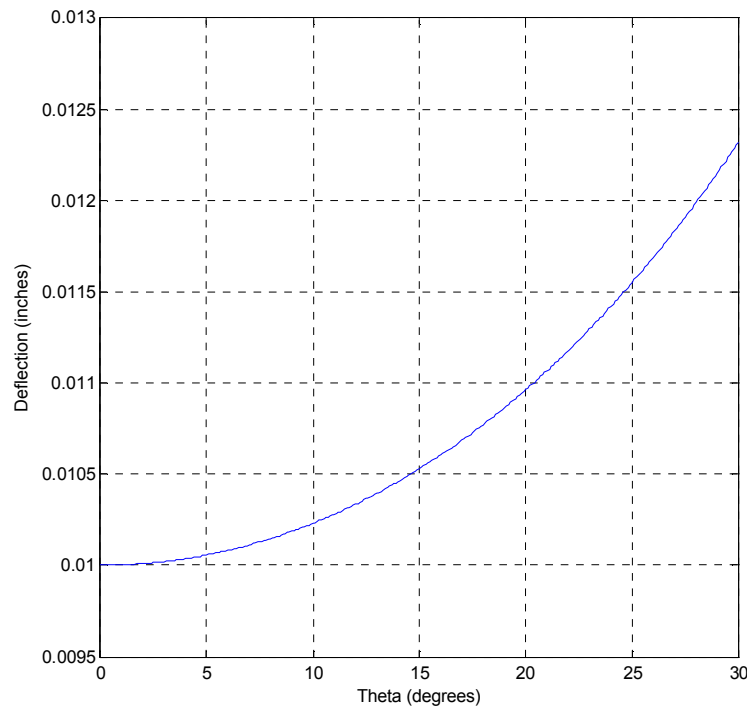
0.004" gap



0.016" gap

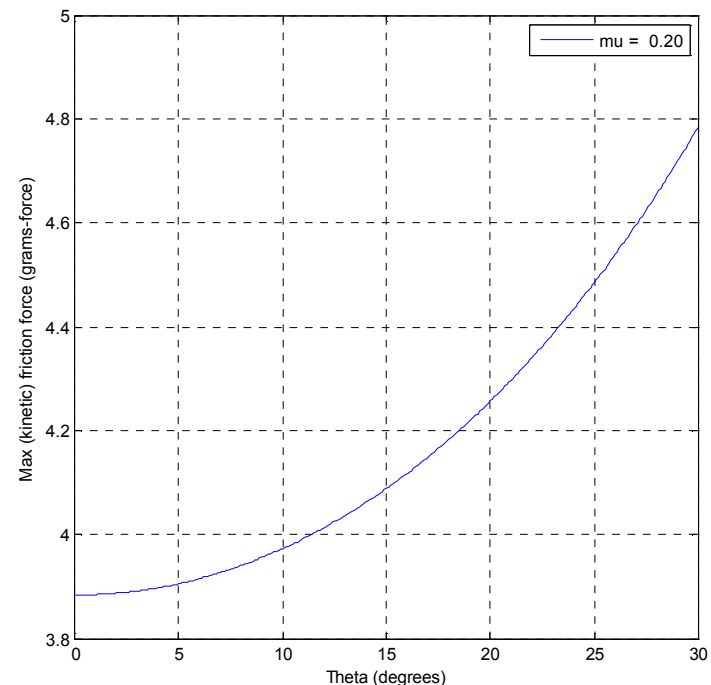
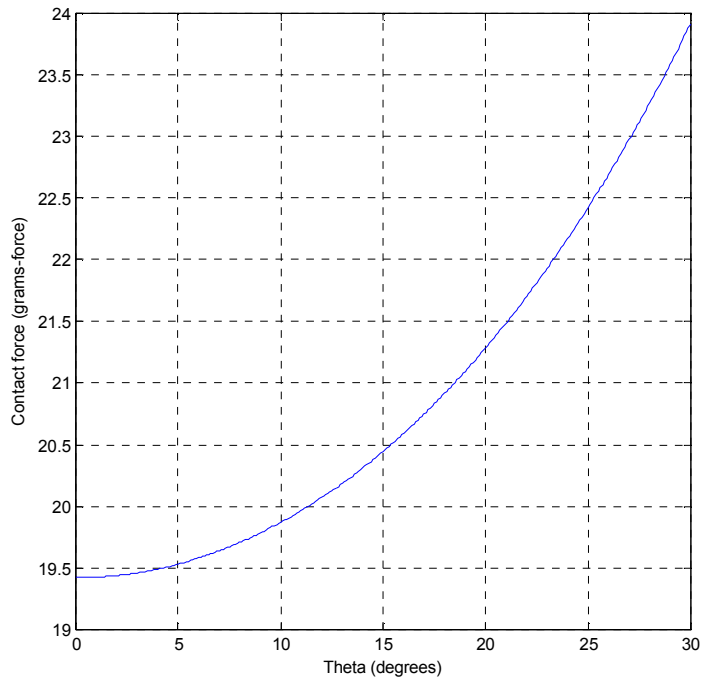
Sensitivity Study – Receptacle Misalignment

- **What if the receptacle is angled and therefore misaligned relative to the pin?**



Sensitivity Study – Receptacle Misalignment

- What if the receptacle is angled and therefore misaligned relative to the pin?



Receptacle Fixture (OLD)



Soldering – Problems

